

Search Notes

Application/Control No.

10/760,351

Examiner

Hien N. Nguyen

Applicant(s)/Patent under
Reexamination

ONO ET AL.

Art Unit

2824

SEARCHED

Class	Subclass	Date	Examiner
365	185.18	3/28/2005	HN
	185.23		
	185.24		
	185.22		
	185.14		
	185.03		
	185.19		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
365	185.18	4/2/2005	HN
	185.14		
	185.22		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	3/28/2005	HN